PXD TID measurement

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Overview

- Design inst. luminosity at $8 \times 10^{35} \,\mathrm{cm}^{-2} \mathrm{s}^{-1}$
- Expect ionizing dose rate of about $20 \,\mathrm{kGy} \,\mathrm{yr}^{-1}$ at design lumi
- Currently running well below design lumi and dose rate





Overview

Goals:

- Estimate the PXD total ionizing dose (TID) as time series per module
- Find method that applies since the start of Phase 3 to today and beyond
- Using 1 Hz EPICs online PVs and create a robust and lightweight approach

Method:

- Exploit beam decays to obtain constant noise floor and correct occupancy time series
- Apply fit to the corrected occupancy that is dependent on accelerator PVs (currents)
- Get model for noise corrected occupancy
- Propagate model by interpolating coefficients
- Outlier correction using geometric relations, defined by offline analysis template
- The modeled PXD occupancy is then converted to a dose rate and summed

Challenges:

• The major challenge is to correct for noise hits contributing to the PXD occupancy online PV

Noise floor correction

- PXD occupancy PV contains a floor from noisy pixels firing in triggered events
- The noise floor is assumed constant during a physics run but can change from run to run
- The noise floor is usually observed to be non-negligible (> 10% of occupancy)
- Fit heuristic function to 1Hz occupancy during a beam decay with a constant term for noise
- Subtract the determined noise floor from the occupancy of the physics run



Fit model

- The fit parameters describe the expected background (mostly) in dependence of the currents
- Should the beam conditions change drastically (25.Nov 2021) the model loses its validity



Modeled Occupancy

- The modeled occupancy is noise corrected, robust and available over entire time frame
- The impact of previously determined noise floor can be directly observed
- Iteratively increase the time frame that is fitted to improve statistic in fit





Estimate of dose rate from occupancy

• Estimate the PXD module dose rate \dot{R}_i

$$\dot{R}_{i} = \frac{f_{\mathrm{dhh_clock}}}{N_{\mathrm{trg_len}}} \cdot \frac{\overbrace{(O_{i} - O_{\mathrm{noise},i})}^{\mathrm{fit model prediction}}}{100} \cdot k \cdot \langle \frac{E}{A} \rangle_{i} \cdot \frac{1}{V_{\mathrm{pixel}} \rho_{\mathrm{Si}}}$$

 \dot{R}_i

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i	Layer, ladder, sensor	module name
$f_{\rm dhh_clock}$	$76230000{ m Hz}$	DHH clock
$N_{\rm trg_len}$	$_{\text{PXD}_{\text{HXXXX}_{trg}_{len}_{vALUE_{set}}}/\text{default} = 1768$	Trigger length
O_i	PXD_O_HXXXX_AVG_OCC_cur	Occupancy of module
$O_{\mathrm{noise},i}$	default = 0	Noise floor of module
k	$1/6.242 \times 10^{18} \mathrm{eV} \mathrm{J}^{-1}$	conversion eV to J
E	run and module specific	Energy dep. in cluster
A	run and module specific	Size of cluster
$V_{\rm pixel}$	$\begin{array}{l} \mathrm{default_{inner}} = 219 \times 10^{3} \mathrm{\mu m}^{3} \\ \mathrm{default_{outer}} = 300 \times 10^{3} \mathrm{\mu m}^{3} \end{array}$	Mean volume of pixel
$ ho_{ m Si}$	$2.34 imes 10^{-3} { m kg/cm^3}$	Density of silicon

module dose rate

Energy calibration $\langle \frac{E}{A} \rangle$

- $\langle \frac{E}{A} \rangle$ is the mean energy deposition per firing pixel
- The calibration is from Qingyuan's offline analysis
- Energy calibration \sim stable over time
- Example values for exp. 12 run 5934







Result





Summary

- Implemented method for PXD TID estimation using online PXD and Diamond PVs from EPICs
- Noise floor correction: focus on physics runs with beam decays in both rings and fit the noise floor for explicit correction
- Main focus was on the fit model to estimate a noise corrected PXD occupancy using heuristic scaling laws
- A most robust, reliable and fast measurement upon an unreliable data set that suffers from artifacts, archiver compression and missing calibration in an ever-changing environment
- Error of dose rate depends mostly on ecal $\sim 15\,\%,$ then occupancy $<5\,\%$
- The TID data set is uploaded here https://drive.google.com/drive/folders/1X1ye5A1JU3T0KACwVgE94pac6teuEIha?usp=sharing

Backup Result

• Evolution of TID for all modules over the frame of phase 3



Backup Heuristic Fit

- $O = B_H \cdot F_{B,H} + B_L \cdot F_{B,L} + D$, D identifies as noise, no injection (see backup)
- $O_{\text{corr}} = B_H \cdot F_{B,H} + B_L \cdot F_{B,L} + Inj$, already noise corrected (see backup)
- Heuristic background features, T_H , T_L , B_H , B_L , C_L and D are fit parameters
- Injection background is described by fit parameter times beam gate status

